

# MultiADS: Defect-aware Supervision for Multi-type Anomaly Detection and Segmentation in Zero-Shot Learning

## Supplementary Material

### 1. Our approach

In this section, we will further discuss more details regarding our proposed approach, MultiADS.

#### 1.1. Knowledge Base for Anomalies and Defect-Aware Text Prompts Design

We construct text prompts based on the information we obtain from the Knowledge Base for Anomalies (KBA). This allows for leveraging the specificity of the defect type for each product class. The procedure for defect-aware prompt construction is consistently applied to each dataset. It should be noted, however, that the text prompt regarding the normal state and text template are the same for all datasets.

We conduct experiments on three commonly known datasets, namely MVTec-AD [1], VisA [22], MPDD [9], MAD [19], Real-IAD [15]. We construct multiple distinct defect-aware text prompts and 1 for the normal state, for each dataset. We construct text prompts that represent the normal or good state (without defects) of the images, using the following text prompt template:

*normal* = [ "*[cls]*", "*flawless [cls]*", "*perfect [cls]*", "*unblemished [cls]*", "*[cls] without flaw*", "*[cls] without defect*", "*[cls] without damage*", "*[cls] with immaculate quality*", "*[cls] without any imperfections*", "*[cls] in ideal condition*" ]

where *[cls]* represents a product class from a given dataset. We apply the same normal state design for all datasets, utilizing the text template as in [2] for all datasets as follows:

*text-template* = [ "*a bad photo of a {}.*", "*a low resolution photo of the {}.*", "*a bad photo of the {}.*", "*a cropped photo of the {}.*", "*a bright photo of a {}.*", "*a dark photo of the {}.*", "*a photo of my {}.*", "*a photo of the cool {}.*", "*a close-up photo of a {}.*", "*a black and white photo of the {}.*", "*a bright photo of the {}.*", "*a cropped photo of a {}.*", "*a jpeg corrupted photo of a {}.*", "*a blurry photo of the {}.*", "*a photo of the {}.*", "*a good photo of the {}.*", "*a photo of one {}.*", "*a close-up photo of the {}.*", "*a photo of a {}.*", "*a low resolution photo of a {}.*", "*a photo of a large {}.*", "*a blurry photo of a {}.*", "*a jpeg corrupted photo of the {}.*", "*a good photo of a {}.*", "*a photo of the small {}.*", "*a photo of the large {}.*", "*a black and white photo of a {}.*", "*a dark photo of a {}.*", "*a photo of a cool {}.*", "*a photo*

*of a small {}.*", "*this is a {} in the scene.*", "*this is the {} in the scene.*", "*this is one {} in the scene.*", "*there is the {} in the scene.*", "*there is a {} in the scene.*" ]

where *{}* is filled with content from the normal and defect-aware text prompts.

An example of a text-prompt representing the normal state for product class *[cls] = cable* is as follows:

$$S_{\text{normal}} = \{ \text{"A bad photo of } \textit{cable} \text{."}, \dots, \text{"There is a } \textit{cable} \text{ in ideal condition in the scene."} \} \quad (1)$$

Similarly, we construct text prompts representing distinct defect types. An example of a text-prompt representing the *bent* defect type for product class *[cls] = cable* is as follows:

$$S_{\text{bent}} = \{ \text{"A bad photo of } \textit{cable} \text{ has a bent defect."}, \dots, \text{"There is a bent edge on cable in the scene."} \} \quad (2)$$

In Tables 1-5, we show the defect-aware text prompts for each defect type for all datasets, respectively. Note that for shared defect types among the datasets, such as *bent*, *hole*, and *scratch*, we use the same defect-aware text prompts among all datasets.

We provide the defined defect-aware text prompts, attached to the source code. The simplest way is to adapt the defect-aware information in a suitable manner based on the design of other approaches that aim to investigate defect types in anomaly detection tasks.

In the main manuscript, we mention that the KBA contains the information for defect variations and defect type properties (attributes). Also, we include synonyms of defect types such as *a slight curve*, which can also help VLMs to capture the similarity between image-text pairs. Likewise, we apply the same strategy for the construction of defect-aware text prompts for all defect types. More examples are provided in Tables 1-5. Additionally, Tables 7-12 show variations of each defect type observed from all given datasets, for example *bent* contains variations *bent lead*, *bent wire*, and *bent edge*.

Table 1. Defect-Aware text prompts for all defect types of the VisA dataset. *[cls]* represents a variable that takes as value all product classes in the VisA dataset.

Defect Type	Defect-Aware Text Prompts	Defect Type	Defect-Aware Text Prompts
Bent	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a bent defect”</li> <li>“flawed <i>[cls]</i> with a bent lead”</li> <li>“a bend found in <i>[cls]</i>”</li> <li>“<i>[cls]</i> has a slight curve defect”</li> <li>“<i>[cls]</i> with noticeable bending”</li> <li>“a bent wire on <i>[cls]</i>”</li> </ul>	Broken	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a breakage defect”</li> <li>“broken <i>[cls]</i>”</li> <li>“<i>[cls]</i> with broken defect”</li> <li>“<i>[cls]</i> shows breakage”</li> <li>“broken or cracked areas on <i>[cls]</i>”</li> <li>“visible breakage on <i>[cls]</i>”</li> </ul>
Bubble	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with bubbles defect”</li> <li>“bubbles seen on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with bubble marks”</li> <li>“air bubbles in <i>[cls]</i>”</li> <li>“<i>[cls]</i> contains bubble defects”</li> <li>“small bubbles on <i>[cls]</i> surface”</li> </ul>	Burnt	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a burnt defect”</li> <li>“<i>[cls]</i> shows burn marks”</li> <li>“burnt areas on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with signs of burning”</li> <li>“scorch marks on <i>[cls]</i>”</li> <li>“<i>[cls]</i> appears slightly burnt”</li> </ul>
Chip	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with chip defect”</li> <li>“<i>[cls]</i> with fragment broken defect”</li> <li>“chipped areas on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with chipped parts”</li> <li>“broken fragments on <i>[cls]</i>”</li> <li>“chip marks found on <i>[cls]</i>”</li> </ul>	Crack	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a crack defect”</li> <li>“<i>[cls]</i> has a visible crack”</li> <li>“cracked areas on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with surface cracking”</li> <li>“fine cracks found on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows crack lines”</li> </ul>
Damage	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a damaged defect”</li> <li>“flawed <i>[cls]</i> with damage”</li> <li>“<i>[cls]</i> shows signs of damage”</li> <li>“damage found on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with visible wear and tear”</li> <li>“<i>[cls]</i> with structural damage”</li> </ul>	Extra	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with extra thing”</li> <li>“<i>[cls]</i> has a defect with extra thing”</li> <li>“extra material on <i>[cls]</i>”</li> <li>“<i>[cls]</i> contains additional pieces”</li> <li>“<i>[cls]</i> with extra component defect”</li> <li>“unwanted additions on <i>[cls]</i>”</li> </ul>
Hole	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a hole defect”</li> <li>“a hole on <i>[cls]</i>”</li> <li>“visible hole on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has small punctures”</li> <li>“<i>[cls]</i> shows perforations”</li> <li>“hole present on <i>[cls]</i>”</li> </ul>	Melded	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with melded defect”</li> <li>“melded parts on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has fused areas”</li> <li>“fused spots on <i>[cls]</i>”</li> <li>“melded areas on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with melded material”</li> </ul>
Melt	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with melt defect”</li> <li>“melted areas on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows melting”</li> <li>“signs of melting on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with melted spots”</li> <li>“<i>[cls]</i> has a melted appearance”</li> </ul>	Missing	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a missing defect”</li> <li>“flawed <i>[cls]</i> with something missing”</li> <li>“<i>[cls]</i> has missing parts”</li> <li>“missing components on <i>[cls]</i>”</li> <li>“absent pieces in <i>[cls]</i>”</li> <li>“<i>[cls]</i> is incomplete”</li> </ul>
Partical	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with particles defect”</li> <li>“<i>[cls]</i> has foreign particles”</li> <li>“small particles on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with unwanted particles”</li> <li>“contaminants found on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with visible particles”</li> </ul>	Scratch	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a scratch defect”</li> <li>“flawed <i>[cls]</i> with a scratch”</li> <li>“scratches visible on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has surface scratches”</li> <li>“small scratches found on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with scratch marks”</li> </ul>
Spot	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with spot defect”</li> <li>“spots visible on <i>[cls]</i>”</li> <li>“flawed <i>[cls]</i> with spots”</li> <li>“<i>[cls]</i> with visible spotting”</li> <li>“<i>[cls]</i> shows small spots”</li> <li>“surface spots on <i>[cls]</i>”</li> </ul>	Stuck	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a stuck defect”</li> <li>“<i>[cls]</i> stuck together”</li> <li>“<i>[cls]</i> has stuck parts”</li> <li>“adhesive issue causing <i>[cls]</i> to stick”</li> <li>“<i>[cls]</i> is partially stuck”</li> <li>“<i>[cls]</i> with adhesion defect”</li> </ul>
Weird Wick	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with a weird wick defect”</li> <li>“<i>[cls]</i> has an unusual wick”</li> <li>“the wick on <i>[cls]</i> appears odd”</li> <li>“<i>[cls]</i> with a strangely shaped wick”</li> <li>“irregular wick found on <i>[cls]</i>”</li> <li>“odd wick defect on <i>[cls]</i>”</li> </ul>	Wrong Place	<ul style="list-style-type: none"> <li>“<i>[cls]</i> with defect that something on wrong place”</li> <li>“<i>[cls]</i> has a misplaced defect”</li> <li>“flawed <i>[cls]</i> with misplacing”</li> <li>“misaligned part on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows parts out of place”</li> <li>“misplacement detected on <i>[cls]</i>”</li> </ul>



Table 2. Defect-Aware text prompts for all defect types of the MVTec-AD dataset. *[cls]* represents a variable that takes as value all product classes in the MVTec-AD dataset.

Defect Type	Defect-Aware Text Prompts	Defect Type	Defect-Aware Text Prompts
Bent	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a bent defect”</li> <li>“flawed <i>[cls]</i> with a bent lead”</li> <li>“a bend found in <i>[cls]</i>”</li> <li>“<i>[cls]</i> has a slight curve defect”</li> <li>“<i>[cls]</i> with noticeable bending”</li> <li>“a bent wire on <i>[cls]</i>”</li> </ul>	Broken	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a broken defect”</li> <li>“flawed <i>[cls]</i> with breakage”</li> <li>“visible breakage on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with broken areas”</li> <li>“<i>[cls]</i> shows signs of breaking”</li> <li>“cracked or broken spots on <i>[cls]</i>”</li> </ul>
Color	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a color defect”</li> <li>“inconsistent color on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with color discrepancies”</li> <li>“<i>[cls]</i> has a noticeable color difference”</li> <li>“<i>[cls]</i> with irregular coloring”</li> <li>“<i>[cls]</i> has off-color patches”</li> </ul>	Contamination	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a contamination defect”</li> <li>“foreign particles on <i>[cls]</i>”</li> <li>“<i>[cls]</i> is contaminated”</li> <li>“<i>[cls]</i> contains contaminants”</li> <li>“<i>[cls]</i> has impurity issues”</li> <li>“traces of contamination on <i>[cls]</i>”</li> </ul>
Crack	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a crack defect”</li> <li>“a crack is present on <i>[cls]</i>”</li> <li>“cracked area on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with noticeable cracking”</li> <li>“fine cracks found on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows surface cracks”</li> </ul>	Cut	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a cut defect”</li> <li>“cut marks on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with visible cuts”</li> <li>“a cut detected on <i>[cls]</i>”</li> <li>“<i>[cls]</i> is sliced or cut”</li> <li>“surface cut seen on <i>[cls]</i>”</li> </ul>
Damaged	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a damaged defect”</li> <li>“flawed <i>[cls]</i> with damage”</li> <li>“<i>[cls]</i> with visible damage”</li> <li>“damaged areas on <i>[cls]</i>”</li> <li>“physical damage seen on <i>[cls]</i>”</li> <li>“noticeable wear on <i>[cls]</i>”</li> </ul>	Fabric	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a fabric defect”</li> <li>“<i>[cls]</i> has a fabric border defect”</li> <li>“<i>[cls]</i> has a fabric interior defect”</li> <li>“fabric quality issues on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with textile irregularities”</li> <li>“fabric borders on <i>[cls]</i> show defects”</li> </ul>
Faulty Imprint	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a faulty imprint defect”</li> <li>“<i>[cls]</i> has a print defect”</li> <li>“incorrect printing on <i>[cls]</i>”</li> <li>“misaligned print on <i>[cls]</i>”</li> <li>“printing errors present on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has a blurred print defect”</li> </ul>	Glue	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a glue defect”</li> <li>“<i>[cls]</i> has a glue strip defect”</li> <li>“excess glue on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with uneven glue application”</li> <li>“<i>[cls]</i> has visible glue spots”</li> <li>“misplaced glue seen on <i>[cls]</i>”</li> </ul>
Hole	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a hole defect”</li> <li>“a hole on <i>[cls]</i>”</li> <li>“visible hole on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with punctures”</li> <li>“small hole found in <i>[cls]</i>”</li> <li>“perforations present on <i>[cls]</i>”</li> </ul>	Liquid	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a liquid defect”</li> <li>“flawed <i>[cls]</i> with liquid”</li> <li>“<i>[cls]</i> with oil”</li> <li>“liquid marks on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with liquid residue”</li> <li>“stains from liquid on <i>[cls]</i>”</li> </ul>
Misplaced	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a misplaced defect”</li> <li>“flawed <i>[cls]</i> with misplacing”</li> <li>“<i>[cls]</i> shows misalignment”</li> <li>“misplaced parts on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with incorrect positioning”</li> <li>“positioning defects on <i>[cls]</i>”</li> </ul>	Missing	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a missing defect”</li> <li>“flawed <i>[cls]</i> with something missing”</li> <li>“<i>[cls]</i> has missing components”</li> <li>“missing parts on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows absent pieces”</li> <li>“certain parts missing from <i>[cls]</i>”</li> </ul>
Poke	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a poke defect”</li> <li>“<i>[cls]</i> has a poke insulation defect”</li> <li>“visible poke mark on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has puncture marks”</li> <li>“a poke flaw on <i>[cls]</i>”</li> <li>“small poke defect on <i>[cls]</i>”</li> </ul>	Rough	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a rough defect”</li> <li>“rough texture on <i>[cls]</i>”</li> <li>“uneven surface on <i>[cls]</i>”</li> <li>“<i>[cls]</i> is coarser than expected”</li> <li>“surface roughness seen on <i>[cls]</i>”</li> <li>“texture defects on <i>[cls]</i>”</li> </ul>
Scratch	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a scratch defect”</li> <li>“flawed <i>[cls]</i> with a scratch”</li> <li>“visible scratches on <i>[cls]</i>”</li> <li>“<i>[cls]</i> with surface scratches”</li> <li>“minor scratches seen on <i>[cls]</i>”</li> <li>“<i>[cls]</i> shows scratch marks”</li> </ul>	Squeeze	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a squeeze defect”</li> <li>“flawed <i>[cls]</i> with a squeeze”</li> <li>“squeezed area on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has compression marks”</li> <li>“<i>[cls]</i> appears squeezed”</li> <li>“flattened areas on <i>[cls]</i>”</li> </ul>
Thread	<ul style="list-style-type: none"> <li>“<i>[cls]</i> has a thread defect”</li> <li>“flawed <i>[cls]</i> with a thread”</li> <li>“loose threads on <i>[cls]</i>”</li> <li>“<i>[cls]</i> has visible threads”</li> <li>“untrimmed threads on <i>[cls]</i>”</li> <li>“threads sticking out on <i>[cls]</i>”</li> </ul>		

Table 3. Defect-Aware text prompts for all defect types of the MPDD dataset. *[cls]* represents a variable that takes as value all product classes in the MPDD dataset.

Defect Type	Defect-Aware Text Prompts	Defect Type	Defect-Aware Text Prompts
Bent	“[cls] has a bent defect” “flawed [cls] with a bent lead” “a bend found in [cls]” “[cls] has a slight curve defect” “[cls] with noticeable bending” “a bent wire on [cls]”	Defective Painting	“[cls] with a defective painting defect” “flawed [cls] with painting imperfections” “[cls] has painting inconsistencies” “uneven painting on [cls]” “[cls] shows poor paint quality” “paint defects present on [cls]”
Flattening	“[cls] becomes flattened” “[cls] has a flatten defect” “flattening observed on [cls]” “[cls] appears compressed” “[cls] is flattened or squashed” “deformation detected on [cls]”	Hole	“[cls] with a hole defect” ‘a hole on [cls]’ ‘visible hole in [cls]’ “[cls] with puncture marks” ‘hole detected in [cls]’ “[cls] has small perforations”
Mismatch	“[cls] with bend and parts mismatch defect” “[cls] with parts mismatch defect” “[cls] has mismatched parts” “mismatched components on [cls]” “bend and parts misalignment in [cls]” “[cls] shows part misplacement”	Rust	“[cls] with a rust defect” “[cls] has rust patches” “rust spots on [cls]” “visible rust on [cls]” “[cls] shows signs of rusting” “[cls] affected by corrosion”
Scratch	“[cls] has a scratch defect” “flawed [cls] with a scratch” ‘scratches visible on [cls]’ “[cls] with surface scratches” “[cls] has scratch marks” “minor scratches found on [cls]”		

Table 4. Defect-Aware text prompts for all defect types of the MAD dataset. *[cls]* represents a variable that takes as value all product classes in the MAD dataset.

Defect Type	Defect-Aware Text Prompts	Defect Type	Defect-Aware Text Prompts
Burr	“[cls] has a burr defect” “sharp burr found on [cls]” “[cls] has excess material on edges” “burr formation detected on [cls]” “[cls] exhibits rough edges” “[cls] shows protruding material”	Missing	“[cls] has a missing defect” “flawed [cls] with something missing” “[cls] has missing components” “missing parts on [cls]” “[cls] shows absent pieces” “certain parts missing from [cls]”
Stain	“[cls] with a stain defect” “inconsistent color on [cls]” “[cls] with color discrepancies”		

## 2. Datasets

Due to space limitations in the main manuscript, here we describe in detail the industrial anomaly detection datasets: MVTec-AD [1], VisA [22], MPDD [9], MAD (simulated and real) [19], and Real-IAD [15]. Key statistics on the datasets are shown in Table 6, such as categories, distinct classes, and the number of samples. MVTec-AD dataset consists of two categories, namely objects and textures, and 15 product classes. For each product, there can be a different number of defects, as shown in Table 7. This number varies from 1 up to 8, but for the textures, it is 5 for all products. We classify each defect to the defect type as we defined before.

Additionally, we provide more details about defect types in order to highlight the importance and the de-

sign of our defect-aware text prompts. Thus, details of the VisA datasets are shown in Table 8; the products are categorized into complex structures, multiple instances (an image with multiple products of the same class, e.g., multiple candles, multiple capsules), and single instances. In total, it consists of 130 defect types if we consider different combinations of defect types, but if we consider the combination as a single defect type, then the VisA dataset has 84 defect types and 40 distinct defect types. In Table 8, some defect types are included as part of the *Combined* defect type, which consists of multiple defect types. The number of defect types for each product varies between 5 and 9 defect types. In Table 9, we show detailed information regarding the MPDD dataset, which consists of 6 product types and 11

Table 5. Defect-Aware text prompts for all defect types of the Real-IAD dataset.  $[cls]$  represents a variable that takes as value all product classes in the Real-IAD dataset.

Defect Type	Defect-Aware Text Prompts	Defect Type	Defect-Aware Text Prompts
Pit	<p>“<math>[cls]</math> has a pit defect”</p> <p>“Small cavities or pits detected on <math>[cls]</math>”</p> <p>“<math>[cls]</math> with color discrepancies”</p>	Scratch	<p>“<math>[cls]</math> has a scratch defect”</p> <p>“flawed <math>[cls]</math> with a scratch”</p> <p>“scratches visible on <math>[cls]</math>”</p> <p>“<math>[cls]</math> with surface scratches”</p> <p>“<math>[cls]</math> has scratch marks”</p> <p>“minor scratches found on <math>[cls]</math>”</p>
Deformation	<p>“<math>[cls]</math> has a deformation defect”</p> <p>“<math>[cls]</math> appears twisted or misshaped”</p> <p>“Structural distortion detected on <math>[cls]</math>”</p> <p>“Unexpected shape deformation found in <math>[cls]</math>”</p> <p>“<math>[cls]</math> exhibits rough edges”</p> <p>“<math>[cls]</math> shows signs of bending under stress”</p>	Deformation	<p>“<math>[cls]</math> has an abrasion defect”</p> <p>“<math>[cls]</math> has noticeable or scuffing”</p> <p>“<math>[cls]</math> is affected by continuous rubbing”</p> <p>“Worn or scraped areas found on <math>[cls]</math>”</p>
Damaged	<p>“<math>[cls]</math> has a damaged defect”</p> <p>“flawed <math>[cls]</math> with damage”</p> <p>“<math>[cls]</math> with visible damage”</p> <p>“damaged areas on <math>[cls]</math>”</p> <p>“physical damage seen on <math>[cls]</math>”</p> <p>“noticeable wear on <math>[cls]</math>”</p>	Missing	<p>“<math>[cls]</math> has a missing defect”</p> <p>“flawed <math>[cls]</math> with something missing”</p> <p>“<math>[cls]</math> has missing components”</p> <p>“missing parts on <math>[cls]</math>”</p> <p>“<math>[cls]</math> shows absent pieces”</p> <p>“certain parts missing from <math>[cls]</math>”</p>
Foreign	<p>“<math>[cls]</math> has foreign objects defect”</p> <p>“<math>[cls]</math> has a foreign defect”</p> <p>“Unexpected foreign material on <math>[cls]</math>”</p> <p>“<math>[cls]</math> contains an unwanted foreign object”</p> <p>“<math>[cls]</math> with extra thing”</p> <p>“<math>[cls]</math> has a defect with extra thing”</p>	Contamination	<p>“<math>[cls]</math> has a contamination defect”</p> <p>“foreign particles on <math>[cls]</math>”</p> <p>“<math>[cls]</math> is contaminated”</p> <p>“<math>[cls]</math> contains contaminants”</p> <p>“<math>[cls]</math> has impurity issues”</p> <p>“traces of contamination on <math>[cls]</math>”</p>

Table 6. Key statistics on the datasets.

Dataset	Category	$ \mathcal{C} $	Normal / Anomalous Samples
MVTec-AD [1]	Object Texture	15	4,096 / 1,258
VisA [22]	Object	12	9,621 / 1,200
MPDD [9]	Object	6	1,064 / 282
MAD [19]	Object	20	5,231 / 4,902
Real-IAD [15]	Object	30	99,721 / 51,329

defect types, from which 8 are distinct defect types. The number of defect types for each product varies between 1 and 3 defect types. The MAD dataset consists of multi-purpose views of twenty LEGO toys (product classes), with up to three anomaly types. It has simulated and real images. The Real-IAD dataset consists of thirty product categories, up to four defect types per category, and a larger proportion of defect area and range of defect ratios than other datasets. We utilize single-view image data. The details are illustrated in Table 6.

We apply the default normalization of CLIP [13] to all datasets. After normalization, we resize the images to a resolution of (518, 518) to obtain an appropriate visual feature map resolution.

Table 7. Detailed statistics on the MVTec-AD dataset.

Category	Product	Defects	Defect Type	Original Test	
				Anomalous	Normal
Objects	Bottle	Broken Large	Broken	20	20
		Broken Small	Broken	22	
		Contamination	Contamination	21	
	Cable	Bent Wire	Bent	13	58
		Cable Swap	Misplaced	12	
		Combined	Combined	11	
		Cut Inner Insulation	Cut	14	
		Cut Outer Insulation	Cut	10	
		Missing Cable	Missing	12	
	Capsule	Missing Wire	Missing	10	23
		Poke Insulation	Poke	10	
		Crack	Crack	23	
	Hazelnut	Faulty Imprint	Faulty Imprint	22	40
		Poke	Poke	21	
		Scratch	Scratch	23	
		Squeeze	Squeeze	20	
	Metal Nut	Crack	Crack	18	22
		Cut	Cut	17	
		Hole	Hole	18	
		Print	Faulty Imprint	17	
Textures	Pill	Bent	Bent	25	26
		Color	Color	22	
		Flip	Misplaced	23	
		Scratch	Scratch	23	
	Screw	Color	Color	25	41
		Combined	Combined	17	
		Contamination	Contamination	21	
		Crack	Crack	26	
	Toothbrush	Faulty Imprint	Faulty Imprint	19	30
		Pill Type	Damaged	9	
		Scratch	Scratch	24	
		Manipulated Front	Bent	24	60
	Transistor	Scratch Head	Scratch	24	
		Scratch Neck	Scratch	25	
		Thread Side	Thread	23	
	Zipper	Thread Top	Thread	23	32
		Defective	Damaged	12	
		Bent Lead	Bent	10	
		Cut Lead	Cut	10	
	Carpet	Damaged Case	Damaged	10	21
		Misplaced	Misplaced	10	
		Broken Teeth	Broken	19	
		Combined	Combined	16	
	Grid	Fabric Border	Fabric	17	32
		Fabric Interior	Fabric	16	
		Rough	Rough	17	
		Split Teeth	Misplaced	18	
	Leather	Squeezed Teeth	Squeezed	16	33
		Color	Color	19	
		Cut	Cut	17	
		Hole	Hole	17	
	Tile	Metal Contamination	Contamination	17	19
		Thread	Thread	19	
		Bent	Broken	12	
		Broken	Broken	12	
	Wood	Glue	Glue	11	32
		Glue	Glue	11	
		Metal Contamination	Contamination	11	
		Thread	Thread	11	
	Leather	Color	Color	19	32
		Cut	Cut	19	
		Fold	Misplaced	17	
		Glue	Glue	19	
	Tile	Poke	Poke	18	33
		Crack	Crack	17	
		Glue Strip	Glue	18	
		Gray Stroke	Damaged	16	
	Wood	Oil	Liquid	18	19
		Rough	Rough	15	
		Color	Color	8	
		Combined	Combined	11	
	Carpet	Hole	Hole	10	32
		Liquid	Liquid	10	
		Scratch	Scratch	21	
		Scratch	Scratch	21	

Table 8. Detailed statistics on the VisA dataset. We relabeled every image originally marked as “combined” in the VisA dataset by identifying each individual defect it contains and assigning the image to all corresponding defect categories.

Category	Product	Defects	Defect Type	Test	
				Anomalous	Normal
Complex Structure	Pcb1	Bent	Bent	15	100
		Melt	Melt	52	
		Missing	Missing	20	
	Pcb2	Scratch	Scratch	21	100
		Bent	Bent	15	
		Melt	Melt	54	
	Pcb3	Missing	Missing	19	101
		Scratch	Scratch	19	
		Bent	Bent	20	
	Pcb4	Melt	Melt	41	101
		Missing	Missing	20	
		Scratch	Scratch	25	
Multiple Instances	Candle	Burnt	Burnt	8	100
		Scratch	Scratch	17	
		Dirt	Dirt	39	
	Capsules	Damage	Damage	19	101
		Extra	Extra	26	
		Missing	Missing	33	
	Macaroni1	Wrong Place	Wrong Place	12	100
		Chunk of Wax Missing	Missing	15	
		Damaged Corner of Packaging	Damaged	25	
	Macaroni2	Different Colour Spot	Spot	22	60
		Extra Wax in Candle	Extra	9	
		Foreign Particals on Candle	Particals	17	
Single Instance	Cashew	Wax Melded Out of the Candle	Melded	13	50
		Weird Candle Wick	Weird Wick	11	
		Bubble	Bubble	49	
	Fryum	Discolor	Discolor	15	50
		Scratch	Scratch	15	
		Leak	Leak	20	
	Pipe Fryum	Misheap	Damaged	20	50
		Chip Around Edge and Corner	Chip	25	
		Different Colour Spot	Spot	37	
	Chewinggum	Similar Colour Spot	Spot	14	50
		Small Cracks	Crack	10	
		Middle Breakage	Broken	27	
Single Instance	Cashew	Small Scratches	Scratches	27	50
		Breakage down the Middle	Broken	10	
		Color Spot Similar to the Object	Spot	35	
	Fryum	Different Color Spot	Spot	25	50
		Small Chip Around Edge	Chip	25	
		Small Cracks	Cracks	12	
	Pipe Fryum	Small Scratches	Scratches	25	50
		Burnt	Burnt	15	
		Corner or Edge Breakage	Broken	25	
	Chewinggum	Middle Breakage	Broken	25	50
		Different Colour Spot	Spot	25	
		Same Colour Spot	Spot	28	
Single Instance	Cashew	Small Holes	Hole	9	50
		Small Scratches	Scratch	20	
		Stuck Together	Stuck	6	
	Fryum	Chunk of Gum Missing	Missing	70	50
		Corner Missing	Missing	14	
		Scratches	Scratch	25	
	Pipe Fryum	Similar Colour Spot	Spot	28	50
		Small Cracks	Crack	9	
		Burnt	Burnt	30	
	Chewinggum	Corner or Edge Breakage	Broken	36	50
		Middle Breakage	Broken	20	
		Different Colour Spot	Spot	16	
Single Instance	Cashew	Similar Colour Spot	Spot	36	50
		Small Cracks	Crack	28	
		Burnt	Burnt	9	
	Fryum	Corner or Edge Breakage	Broken	30	50
		Middle Breakage	Broken	36	
		Different Colour Spot	Spot	20	
	Pipe Fryum	Similar Colour Spot	Spot	31	50
		Small Cracks	Crack	22	
		Stuck Together	Stuck	10	
	Chewinggum	Small Scratches	Scratch	10	50
		Stuck Together	Stuck	10	
		Small Cracks	Crack	10	

Table 9. Detailed statistics on the MPDD dataset.

Product	Defects	Defect Type	Original Test	
			Anomalous	Normal
Bracket Black	Hole Scratches	Hole Scratch	12 35	32
Bracket Brown	Bend Mismatch Parts Mismatch	Mismatch Mismatch	17 45	26
Bracket White	Defective Painting Scratches	Defective Painting Scratch	13 17	30
Connector	Parts Mismatch	Mismatch	14	30
Metal Plate	Major Rust	Rust	14	26
	Scratches	Scratch	34	
	Total Rust	Rust	23	
Tubes	Anomalous	Flattening	69	32

Table 10. Detailed statistics on the MAD-real dataset.

Product	Defects	Defect Type	Original Test	
			Anomalous	Normal
Bear	Stains	Stains	24	5
Bird	Missing	Missing	22	5
Elephant	Missing	Missing	18	5
Parrot	Missing	Missing	23	5
Puppy	Stains	Stains	20	5
Scorpion	Missing	Missing	23	5
Turtle	Stains	Stains	21	5
Unicorn	Missing	Missing	21	5
Whale	Stains	Stains	32	5

Table 11. Detailed statistics on the MAD-sim dataset.

Product	Defects	Defect Type	Original Test	
			Anomalous	Normal
Bear	Burrs	Burrs	88	36
	Missing	Missing	112	
	Stains	Stains	59	
Bird	Burrs	Burrs	51	30
	Missing	Missing	160	
	Stains	Stains	40	
Cat	Burrs	Burrs	98	36
	Missing	Missing	151	
	Stains	Stains	58	
Elephant	Burrs	Burrs	72	36
	Missing	Missing	149	
	Stains	Stains	55	
Gorilla	Burrs	Burrs	67	20
	Missing	Missing	137	
	Stains	Stains	35	
Mallard	Burrs	Burrs	27	20
	Missing	Missing	157	
	Stains	Stains	33	
Obesobeso	Burrs	Burrs	101	36
	Missing	Missing	123	
	Stains	Stains	61	
Owl	Burrs	Burrs	41	30
	Missing	Missing	115	
	Stains	Stains	44	
Parrot	Burrs	Burrs	29	36
	Missing	Missing	131	
	Stains	Stains	42	
Pheonix	Burrs	Burrs	86	36
	Missing	Missing	150	
	Stains	Stains	69	
Pig	Burrs	Burrs	76	36
	Missing	Missing	138	
	Stains	Stains	70	
Puppy	Burrs	Burrs	63	36
	Missing	Missing	125	
	Stains	Stains	47	
Sabertooth	Burrs	Burrs	58	36
	Missing	Missing	136	
	Stains	Stains	47	
Scorpion	Burrs	Burrs	61	36
	Missing	Missing	121	
	Stains	Stains	53	
Sheep	Burrs	Burrs	39	36
	Missing	Missing	150	
	Stains	Stains	63	
Swan	Burrs	Burrs	66	36
	Missing	Missing	143	
	Stains	Stains	41	
Turtle	Burrs	Burrs	32	20
	Missing	Missing	130	
	Stains	Stains	35	
Unicorn	Burrs	Burrs	55	20
	Missing	Missing	132	
	Stains	Stains	35	
Whale	Burrs	Burrs	71	30
	Missing	Missing	127	
	Stains	Stains	53	
Zalika	Burrs	Burrs	56	36
	Missing	Missing	130	
	Stains	Stains	57	

Table 12. Detailed statistics on the Real-IAD dataset (Part I).

Product	Defects	Defect Type	Original Test	
			Normal	Anomalous
Audiojack	Deformation	Deformation	398	126
	Scratch	Scratch		4
	Missing	Missing		56
	Contamination	Contamination		27
Bottle Cap	Pit	Pit	369	65
	Scratch	Scratch		125
	Missing Parts	Missing Parts		1
	Contamination	Contamination		73
Button Battery	Pit	Pit	291	123
	Abrasion	Abrasion		68
	Scratch	Scratch		109
	Contamination	Contamination		117
End Cap	Scratch	Scratch	289	92
	Damage	Damage		119
	Missing Parts	Missing Parts		133
	Contamination	Contamination		80
Eraser	Pit	Pit	389	36
	Scratch	Scratch		101
	Missing Parts	Missing Parts		30
	Contamination	Contamination		68
Fire Hood	Pit	Pit	418	33
	Scratch	Scratch		51
	Missing Parts	Missing Parts		62
	Contamination	Contamination		23
Mint	Missing Parts	Missing Parts	305	111
	Foreign Objects	Foreign Objects		197
	Contamination	Contamination		142
Mounts	Pit	Pit	385	30
	Missing Parts	Missing Parts		131
	Contamination	Contamination		79
Pcb	Scratch	Scratch	278	103
	Missing Parts	Missing Parts		104
	Foreign Objects	Foreign Objects		129
	Contamination	Contamination		109
Phone Battery	Pit	Pit	349	38
	Scratch	Scratch		28
	Damage	Damage		125
	Contamination	Contamination		110
Plastic Nut	Pit	Pit	442	14
	Scratch	Scratch		13
	Missing Parts	Missing Parts		56
	Contamination	Contamination		35
Plastic Plug	Pit	Pit	368	121
	Scratch	Scratch		58
	Missing Parts	Missing Parts		31
	Contamination	Contamination		52
Porcelain Doll	Abrasion	Abrasion	402	64
	Scratch	Scratch		43
	Contamination	Contamination		89
Regulator	Scratch	Scratch	477	3
	Missing Parts	Missing Parts		63
	Pit	Pit		170
	Contamination	Contamination		172
Rolled Strip Base	Missing Parts	Missing Parts	250	167
	Contamination	Contamination		172
Sim Card Set	Abrasion	Abrasion	305	148
	Scratch	Scratch		80
	Contamination	Contamination		168
Switch	Scratch	Scratch	266	164
	Missing Parts	Missing Parts		152
	Contamination	Contamination		161
Tape	Damage	Damage	397	128
	Missing Parts	Missing Parts		76
	Contamination	Contamination		21

Table 13. Detailed statistics on the Real-IAD dataset (Part II).

Product	Defects	Defect Type	Original Test	
			Normal	Anomalous
Terminalblock	Pit	Pit	308	142
	Missing Parts	Missing Parts		145
	Contamination	Contamination		106
Toothbrush	Abrasion	Abrasion	272	170
	Missing Parts	Missing Parts		137
	Contamination	Contamination		149
Toy	Pit	Pit	250	125
	Scratch	Scratch		127
	Missing Parts	Missing Parts		126
	Contamination	Contamination		126
Toy-brick	Pit	Pit	370	67
	Scratch	Scratch		60
	Missing Parts	Missing Parts		81
	Contamination	Contamination		53
Transistor1	Deformation	Deformation	265	171
	Missing Parts	Missing Parts		164
	Contamination	Contamination		134
U Block	Abrasion	Abrasion	436	20
	Scratch	Scratch		17
	Missing Parts	Missing Parts		44
	Contamination	Contamination		45
Usb	Deformation	Deformation	353	127
	Scratch	Scratch		54
	Missing Parts	Missing Parts		83
	Contamination	Contamination		39
Usb Adaptor	Pit	Pit	361	85
	Abrasion	Abrasion		22
	Scratch	Scratch		62
	Contamination	Contamination		111
Vcpill	Pit	Pit	398	50
	Scratch	Scratch		11
	Missing Parts	Missing Parts		107
	Contamination	Contamination		40
Wooden Beads	Pit	Pit	304	67
	Scratch	Scratch		96
	Missing Parts	Missing Parts		112
	Contamination	Contamination		117
Woodstick	Pit	Pit	442	7
	Scratch	Scratch		12
	Missing Parts	Missing Parts		69
	Contamination	Contamination		28
Zipper	Deformation	Deformation	250	125
	Damage	Damage		121
	Missing Parts	Missing Parts		125
	Contamination	Contamination		129

### 3. Baselines

To demonstrate the performance of MultiADS, we compare MultiADS with broad SOTA baselines. We run experiments for April-GAN [2], and other baseline results are taken from original papers. If the baseline does not report results for a specific dataset, then the results are taken from the latest publication, which includes these results. Details regarding each baseline are given as follows:

- PaDiM [4] utilizes a pre-trained Convolutional Neural Network (CNN) for patch embedding and multivariate Gaussian distributions to get a probabilistic representation for a one-class learning setting, the normal class. Also, it considers the semantic relations of CNN to improve the localization. Results are taken from [2, 16] baselines. Source code is available at <https://github.com/taikiinoue45/PaDiM>.
- CLIP [13] is a powerful zero-shot classification method. Results are taken from [20] baseline, and to perform the anomaly detection task, they use two classes of text prompt templates "A photo of a normal [cls]" and "A photo of an anomalous [cls]", where "cls" denotes the target class name. The anomaly score is computed according to Eq. [1] in the main manuscript. As for anomaly segmentation, they extend the above computation to local visual embedding to derive the segmentation. Source code is available at <https://github.com/openai/CLIP>.
- CLIP-AC [13] employs an ensemble of text prompt templates that are recommended for the ImageNet dataset [13]. Results are taken from [20] baseline, and they average the generated textual embeddings of normal and anomaly classes, respectively, and compute the probability and segmentation in the same way as CLIP. Source code is available at <https://github.com/openai/CLIP>.
- RegAD [6] is a few-shot learning approach that leverages feature registration as a category-agnostic approach. This approach trains a single generalizable model and does not require re-training or parameter fine-tuning for new categories. Results are taken from the original publication. Source code is available at <https://github.com/MediaBrain-SJTU/RegAD>.
- CoOp [18] is a representative method for prompt learning. Results are taken from [20] baseline for zero-shot setting and from [21] for few-shot setting. To adapt CoOp to zero- and few-shot anomaly detection, authors of [20, 21] replace its learnable text prompt templates  $[V_1][V_2] \dots [V_N][cls]$  with normality and abnormality text prompt tem-

plates, where  $V_i$  is the learnable word embeddings. The normality text prompt template is defined as  $[V_1][V_2] \dots [V_N][normal][cls]$ , and the abnormality one is defined as  $[V_1][V_2] \dots [V_N][anomalous][cls]$ . Anomaly probabilities and segmentation are obtained in the same way as for AnomalyCLIP, and all parameters are kept the same as in the original paper. Source code is available at <https://github.com/KaiyangZhou/CoOp>.

- CoCoOp [17] extends the CoOp work by generalizing the learned context to wider unseen classes within the same dataset. CoCoOp learns a lightweight neural network to generate for each image an input-conditional token (vector), and the proposed dynamic prompts adapt to each instance and are less sensitive to class shift. Results are taken from [20] baseline. Source code is available at <https://github.com/KaiyangZhou/CoOp>.
- PatchCore [14] utilizes locally aggregated, mid-level patch features over a local neighborhood to ensure the retention of sufficient spatial context. PatchCore employs a memory bank for patch features to leverage nominal context at test time by using a greedy coreset subsampling. Results are taken from [2] baseline. Source code is available at <https://github.com/amazon-science/patchcore-inspection>
- WinCLIP [8] is a SOTA zero-shot anomaly detection method. Results for zero-shot settings are taken from the original publication and for few-shot settings are taken from [2] baseline. The authors design a large set of text prompt templates specific to anomaly detection and use a window scaling strategy to obtain anomaly segmentation. Source code is available at <https://github.com/caoyunkang/WinClip>.
- April-GAN [2] is an improved version of WinCLIP. We conducted experiments with this approach and all parameters are kept the same as in their paper. April-GAN first adjusts the text prompt templates and then introduces learnable linear projections to improve local visual semantics to derive more accurate segmentation. Source code is available at <https://github.com/ByChelsea/VAND-APRIL-GAN>.
- GraphCore [16] is a few-shot learning approach that utilizes memory banks to store image features. Results are taken from the original publication. They employ graph representation (Graph Neural Networks) to provide a visual isometric invariant feature (VIIF) as an anomaly measurement feature. The VIIF reduces the size of redundant features stored in memory banks. Results are taken from the original publication. The

authors have not provided a link to the source code yet.

- FastRecon [5] is a few-shot learning approach that utilizes a few normal samples as a reference to reconstruct its normal version, and sample alignment helps to detect anomalies. Thus, they propose a regression algorithm with distribution regularization for the transformation estimation. Results are taken from the original publication. Source code is available at <https://github.com/FzJun26th/FastRecon>.
- InCTRL [21] is a vision-language few-shot learning model that proposes an in-context residual learning approach. It aims to distinguish anomalies from normal samples by detecting residuals between test images and in-context few-shot normal sample prompts from the target domain on the fly. Results are taken from the original publication. Source code is available at <https://github.com/mala-lab/InCTRL>.
- PromptAD [12] is a vision-language few-shot learning approach that learns text prompts for anomaly detection. They propose to concatenate anomaly suffixes to transpose the semantics of normal prompts, in order to construct negative samples. They aim to control the distance between normal and abnormal prompt features through a hyperparameter. Results are taken from the original publication. Source code is available at <https://github.com/FuNz-0/PromptAD>.
- AnomalyCLIP [20] is a SOTA zero-shot anomaly detection method. Results are taken from the original publication. This approach learns a vector representation for text prompts for two states: normal and abnormal. They construct two templates of text prompts, object-aware text prompts and object-agnostic text prompts templates. Through an object-agnostic text prompt template, they aim to learn the shared patterns of different anomalies. Results are taken from the original publication. Source code is available at <https://github.com/zqhang/AnomalyCLIP>.

## 4. Experiments

In this section, we provide more details regarding our approach through ablation studies and the experiments that were conducted. We also visualize the results and discuss some insights and limitations of our approach.

### 4.1. Experiment Details

In this subsection, we detail the experimental setup. We use the ViT-L-14-336 CLIP backbone from OpenCLIP [7], pre-trained on the LAION-400M.E32 setting of open-clip. The learning rate is set to 0.001, with a batch size of 8. The stage number  $m = 4$ . The features are selected from layers 6, 12, 18, and 24.

We adopt a transfer learning setting, training the model on one dataset and evaluating it on the remaining. Specifically, we train our model on MVTec-AD and evaluate it on VisA, MPDD, MAD, and Real-IAD, as well as train on VisA and evaluate on MVTec-AD. Other combinations are not included in the results, as most baselines focus on the aforementioned configurations. During training, we exclude all images labeled with “combined” defects, which indicate multiple defects in a single image. This exclusion is due to the datasets providing binary anomaly masks that treat all defects as identical. Since combined defects are relatively rare in the datasets (see Tables 7, 8, 9), we opted to leave them out during training. However, for testing, all images with multiple defects are included to ensure a fair comparison.

### 4.2. Ablation Studies

Here, we will give more details regarding our ablation studies and show additional results of the experiments we have conducted for the multi-type anomaly segmentation (MTAS) task, binary zero-/few-shot anomaly detection task, and zero-batch task.

#### 4.2.1. Global Anomaly Score

To assess the impact of the global anomaly score on anomaly detection, we conducted ablation studies using our MultiADS model without the global anomaly score, referred to as MultiADS-L. As shown in Table 14, removing the global anomaly score leads to a noticeable performance drop in the zero-shot setting. However, the performance drop in the few-shot setting is minimal, likely because the additional information provided by the test data compensates for the absence of global context.

#### 4.2.2. Defect-Aware Text Prompts

To show the importance of the defect-aware text prompts, we conduct experiments on the MPDD dataset with our approach, MultiADS. First, we train our model on the MVTec-AD dataset, with defect-aware text prompts constructed for the MVTec-AD dataset. Then, during the testing phase, instead of using the defect-aware text prompts constructed for the MPDD dataset, we use defect-aware text prompts constructed for the



Table 14. Ablation study for testing without global anomaly score. MultiADS is our proposed method, while MultiADS-L is the ablated version without including the global anomaly score.

Settings	Training → Testing	Method	Image-Level		
			AUROC	F1-max	AP
Zero-shot	MVTec-AD → VisA	MultiADS	83.6	80.3	86.9
		MultiADS-L	82.1 (+1.5)	80.3 (+0.0)	85.8 (+1.1)
	MVTec-AD → MPDD	MultiADS	78.3	79.2	78.4
		MultiADS-L	76.5 (+1.8)	79 (+0.2)	78.1 (+0.3)
Few-shot (k=4)	MVTec-AD → VisA	MultiADS	93.3	89.7	94.3
		MultiADS-L	93.8 (-0.5)	89.6 (+0.1)	94.5 (-0.2)
	MVTec-AD → MPDD	MultiADS	86	87.2	89.4
		MultiADS-L	85.6 (+0.4)	86.8 (+0.4)	89.3 (+0.1)

Table 15. Ablation Study: Results for MultiADS for each product of the MPDD dataset with different defect-aware text prompts from the VisA dataset and the MPDD dataset on few-shot (k=1) anomaly detection and segmentation tasks. Our model is trained on the MVTec-AD dataset. (**Bold** represents the best performer)

Setting	k=1													
MVTec → MPDD	Pixel-Level								Image-Level					
Product	AUROC		F1-max		AP		AUPRO		AUROC		F1-max		AP	
	VisA	MPDD	VisA	MPDD	VisA	MPDD	VisA	MPDD	VisA	MPDD	VisA	MPDD	VisA	MPDD
Bracket_black	96.7	97.2	11.2	18.7	4.5	11.8	88	89.5	63.4	74.6	78.5	81.6	68.6	80.8
Bracket_brown	96	96.2	14.9	17.6	7.5	8.7	91	91.1	60.4	53.3	80	79.7	72.5	71.4
Bracket_white	99.7	99.7	20.7	24.5	12.8	15.2	96.5	96.7	73.4	81.1	75	78.3	77	82.5
Connector	95.9	96.4	35.3	33.9	33.7	32.4	87.2	87.8	92.9	91.4	78.8	82.8	88.9	9.3
Metal_plate	96.3	96.3	74.6	73.1	81.2	74.8	90.6	89.8	99	92	97.9	90.1	99.6	97.2
Tubes	98.7	98.8	69	68.7	71	70.4	95	95.5	97.3	97.6	96.4	95.5	99	99.1
Average	97.2	<b>97.4</b>	37.6	<b>39.4</b>	35.1	<b>35.6</b>	91.4	<b>91.7</b>	81.1	<b>81.7</b>	84.4	<b>84.6</b>	84.3	<b>86.7</b>

VisA dataset. The results are shown in Table 15. We observe that our approach, MultiADS, performs quite well even when we utilize the defect-aware text prompts of the other dataset for all the metrics on pixel-level and image-level on few-shot anomaly detection and segmentation tasks. Also, we note that to achieve the best performance, especially on the image level, it is crucial to employ defect-aware text prompts suitable for the products of the testing dataset, the MPDD dataset.

In addition to the results shown in the main manuscript, in Table 16 we list the segmentation performance for some sample defect types that are seen/unseen during the training phase. We notice that defects such as *stains* and *scratches* are easy to locate and classify, as they also occur on the training dataset - MVTec-AD. For unseen defects like *burrs* and *mismatch*, our model achieves slightly lower accuracy. On the other hand, for other unseen defects such as *flattening*, we perform with high precision for the classification task. These results, similar to results in the main manuscript, reflect that our approach, MultiADS, has generalization ability on large and complex datasets and unseen defects in the training dataset.

Table 16. Results MTAS for zero-shot setting at pixel-level for sample defect-types. The model is trained on the MVTec-AD dataset. - indicates **unseen** defect types while ✓ indicates **seen** defect types during training.

(a) MAD-sim				
	Defects	AUROC	F1-Score	AP
-	Burrs	95.56	1.18	1.67
✓	Missing	86.52	2.56	3.08
✓	Stains	98.19	15.02	9.92
(b) MPDD				
	Defects	AUROC	F1-Score	AP
-	Mismatch	88.44	2.56	1.04
-	Flattening	96.72	36.06	8.33
✓	Scratch	96.67	26.99	20.26

### 4.2.3. Batched Zero-shot Setting

The idea behind the batched zero-shot setting is to utilize all text samples in  $X_{\text{test}}$  without relying on any labels. This approach can be viewed as a form of domain adaptation, enabling the trained model to better align with the target domain. Inspired by the methodology proposed

Table 17. Image level results for batched zero-shot setting. All results are AUROC values (%). The numbers of baselines are taken from AnomalyDINO [3]. 448 and 672 are the resolutions of the input image.

Setting	Method	MVTec	VisA
Batched zero-shot	ACR [10]	85.8	/
	MuSc [11]	<b>97.8</b>	92.8
	AnomalyDINO <sub>(448)</sub> [3]	93.0	89.7
	AnomalyDINO <sub>(672)</sub> [3]	94.2	90.7
	MultiADS (ours)	96.1	<b>93.1</b>

by AnomalyDINO [3], we employ a memory bank to facilitate this adaptation process. For each test sample  $x^{(k)} \in X_{\text{test}}$ , let  $\mathbf{Z}_i^k \in \mathbb{R}^{h \times w \times N_z}$  denote the adapted image patch embeddings at state  $i$  for given image  $x^{(k)}$ . We define memory bank  $\mathcal{M}_i$  as the union of all image patch embeddings at stage  $i$  across the entire text set  $X_{\text{test}}$ :

$$\mathcal{M}_i = \bigcup_{x^{(k)} \in X_{\text{test}}} \{\mathbf{Z}_i^k[a, b] | a \in [h], b \in [w]\}. \quad (3)$$

During testing, for each given image  $x^{(k)}$ , we compute the cosine similarity between its adapted image patch embedding  $\mathbf{Z}_i^k[a, b] \in \mathbb{R}^{N_z}$  and all embeddings in the memory bank  $\mathcal{M}_i \setminus \{\mathbf{Z}_i^k[a, b]\}$ . Since the memory bank may include anomalous features (due to the unlabeled setting), directly selecting the nearest neighbor might not reliably represent nominal behavior. To address this, and based on the assumption that most patches in the memory bank are nominal, we replace the nearest neighbor with the  $k$ -th nearest neighbor, where  $k$  corresponds to the  $\alpha$ -quantile of the similarity scores. Thus, the set of cosine similarity scores is defined as follows:

$$\mathcal{D}(\mathbf{Z}_i^k[a, b], \mathcal{M}_i \setminus \{\mathbf{Z}_i^k[a, b]\}) = \{d(\mathbf{Z}_i^k[a, b], \mathbf{x}) \mid \mathbf{x} \in \mathcal{M}_i \setminus \{\mathbf{Z}_i^k[a, b]\}\}. \quad (4)$$

where  $d(\cdot)$  represents the cosine similarity. The reference anomaly score for image patch embedding  $\mathbf{Z}_i^k[a, b]$  is defined as follows:

$$s(\mathbf{Z}_i^k[a, b]) = q_\alpha(\mathcal{D}(\mathbf{Z}_i^k[a, b], \mathcal{M}_i \setminus \{\mathbf{Z}_i^k[a, b]\})), \quad (5)$$

where  $q_\alpha$  is the  $\alpha$  quantile of the similarity score set. The comparison of our MultiADS approach with other baselines is listed in Table 17.

#### 4.2.4. Backbones

In Table 18, we show the impact of different architectures and resolutions for our proposed approach, MultiADS. To evaluate the performance of our proposed

approach, MultiADS, and other baselines, we perform zero-shot and few-shot anomaly detection and segmentation on five datasets, MVTEC-AD [1], VisA [22], MPDD [9], MAD [19], and Real-IAD [15]. Results of other baselines are taken from the original published papers or the most recent publications. Thus, for some of the baselines, we are missing the evaluation with different metrics, such as F1-max, AP, and AUPRO on pixel-level, or F1-max and AP for image-level.

#### 4.2.5. Additional Results

In Tables 19, 20, and 21, we show results for our approach, MultiADS, and other baselines on a few-shot setting with  $k \in [1, 2, 4, 8]$  on anomaly detection and segmentation tasks on three datasets, VisA, MPDD, and MVTEC-AD, respectively. In Tables 22, 23, and 24, we show results for our approach, MultiADS, on a few-shot setting with  $k \in \{1, 2\}$  on anomaly detection and segmentation tasks for each product of the VisA, MPDD, and MVTEC-AD datasets, respectively. In Tables 25 and 26, we show results for the variant of our approach, MultiADS-F, on the few-shot setting with  $k \in \{1, 2\}$  on anomaly detection and segmentation tasks for each product of the VisA and MPDD datasets, respectively.

Furthermore, in Table 27, we show results for our proposal, MultiADS, and the most recent baseline, AdaCLIP, for all products of the Real-IAD dataset. We note that our proposal outperforms AdaCLIP for all metrics, and the largest improvement of our method is at the image level. Similarly, in Table 28, we show results for our proposal, MultiADS, and the most competitive baseline, April-GAN, for all products of the MAD dataset. We note that our proposal overall outperforms April-GAN for almost all metrics, and the largest improvement of our method is at the pixel level.

#### 4.3. Visualizations

In this subsection, we present additional visualizations of our anomaly segmentation results. We include eight examples of products from the MVTEC-AD, VisA, and MPDD datasets: hazelnut (Figure 1), screw (Figure 2), and leather (Figure 3) from MVTEC-AD; pipe\_fryum (Figure 4), and capsule (Figure 5) from VisA; and connector (Figure 6) and tube (Figure 7) from MPDD. All segmentation visualizations are performed in a few-shot ( $k = 4$ ) setting. Specifically, the models for hazelnut, screw, and leather were trained on the VisA dataset; the models for pipe\_fryum, capsule, and candle were trained on the MVTEC-AD dataset; and the models for connector and tube were trained on the MVTEC-AD dataset. We discuss some insights and limitations in the caption of these figures.

Table 18. Ablation study for training and testing with different architectures/resolutions for BADS. MultiADS applies the ViT-L-14 architecture with a resolution of 336.

Settings	Dataset	Architecture	Resolution	Image-Level		
				AUROC	F1-max	AP
Zero-shot	VisA	ViT-B-16	224	74	76.6	79
		ViT-B-32	224	68.4	74.6	73.5
		ViT-L-14	224	75.2	78.4	80.6
		ViT-L-14	336	83.6	80.3	86.9
	MPDD	ViT-B-16	224	67.7	77.2	74.4
		ViT-B-32	224	60.7	75	68.8
		ViT-L-14	224	71.6	77.8	76.8
		ViT-L-14	336	78.3	79.2	78.4
Few-shot (k=4)	VisA	ViT-B-16	224	90	86	91.9
		ViT-B-32	224	83.1	81.4	85.4
		ViT-L-14	224	92	88	93.5
		ViT-L-14	336	93.3	89.7	94.3
	MPDD	ViT-B-16	224	80.2	81.6	80
		ViT-B-32	224	78.2	83.1	80.2
		ViT-L-14	224	82	82.9	84.3
		ViT-L-14	336	85.6	87.2	89.4

Table 19. Few-shot anomaly detection and segmentation on the VisA Datasets. April-GAN baseline and our model are trained on the MVTEC-AD dataset. (- denotes the results for this metric are not reported in the original paper; **bold** represents the best performer)

Settings		k=1					k=2				
VisA		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	89.9	64.3	62.8	75.3	68.3	92.0	70.1	67.4	75.7	71.6
CoOp	IJCV22	-	-	-	-	-	-	-	83.5	-	-
PatchCore	CVPR23	95.4	80.5	79.9	81.7	82.8	96.1	82.6	81.6	82.5	84.8
WinCLIP	CVPR23	96.4	85.1	83.8	83.1	85.1	96.8	86.2	84.6	83.0	85.8
April-GAN	CVPR23	96.0	90.0	91.2	86.9	93.3	96.2	90.1	92.2	87.7	94.2
PromptAD	CVPR24	96.7	-	86.9	-	-	97.1	-	88.3	-	-
InCTRL	CVPR24	-	-	-	-	-	-	-	87.7	-	-
AnomalyGPT	AAAI24	96.2	-	87.4	-	-	96.4	-	88.6	-	-
MultiADS (ours)		<b>97.1</b>	<b>92.7</b>	91.9	<b>88.3</b>	93.1	<b>97.2</b>	<b>93.1</b>	<b>93.3</b>	<b>89.5</b>	93.9
MultiADS-F (ours)		96.6	91.7	<b>92</b>	88.1	<b>93.9</b>	96.7	91.9	92.8	88.5	<b>94.4</b>

Settings		k=4					k=8				
VisA		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	93.2	72.6	72.8	78.0	75.6	-	-	78.1	-	-
CoOp	IJCV22	-	-	84.2*	-	-	-	-	84.8	-	-
PatchCore	CVPR23	96.8	84.9	85.3	84.3	87.5	-	-	87.3	-	-
WinCLIP	CVPR23	97.2	87.6	87.3	84.2	88.8	-	-	88.0	-	-
April-GAN	CVPR23	96.2	90.2	92.6	88.4	94.5	96.3	90.2	92.7	88.5	94.6
PromptAD	CVPR24	<b>97.4</b>	-	89.1	-	-	-	-	-	-	-
InCTRL	CVPR24	-	-	90.2*	-	-	-	-	90.4	-	-
AnomalyGPT	AAAI24	96.7	-	90.6	-	-	-	-	-	-	-
MultiADS (ours)		96.9	91.1	<b>93.3</b>	<b>89.7</b>	94.3	<b>97.4</b>	<b>93.5</b>	<b>94.7</b>	<b>91.3</b>	94.9
MultiADS-F (ours)		97.0	<b>91.5</b>	92.8	88.5	<b>94.6</b>	96.9	92.1	93.8	89.5	<b>95.1</b>

Table 20. Few-shot anomaly detection and segmentation on the MPDD Dataset. April-GAN baseline and our model are trained on the MVTec-AD dataset. (- denotes the results for this metric are not reported in the original paper; **bold** represents the best performer)

Settings		k=1					k=2				
MPDD		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	73.9	-	57.5	-	-	75.4	-	58.0	-	-
RegAD	ECCV22	92.6	-	60.9	-	-	93.2	-	63.4	-	-
PatchCore	CVPR22	79.4	-	68.9	77.2	-	84.4	-	75.5	81.7	-
April-GAN	CVPR23	96.9	91.4	84.6	<b>86.8</b>	<b>88.6</b>	96.9	91.4	84.6	<b>86.8</b>	88.6
GraphCore	ICLR23	95.2	-	<b>84.7</b>	-	-	95.4	-	85.4	-	-
FastRecon	ICCV23	96.4	-	72.2	79.1	-	96.7	-	76.1	82.8	-
MultiADS (ours)		97.4	91.7	81.7	84.6	86.7	97.7	<b>92.4</b>	<b>86.6</b>	86.6	<b>90.1</b>
MultiADS-F (ours)		<b>97.7</b>	<b>92.2</b>	80.1	82.5	84	<b>97.8</b>	<b>92.4</b>	83.8	85.8	86.9

Settings		k=4					k=8				
MPDD		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	75.9	-	58.3	-	-	76.2	-	58.5	-	-
RegAD	ECCV22	93.9	-	68.8	-	-	95.1	-	71.9	-	-
PatchCore	CVPR22	92.8	-	77.8	82.4	-	92.8	-	77.8	82.4	-
April-GAN	CVPR23	96.9	91.4	84.6	86.8	88.6	96.7	91	86	<b>87.8</b>	<b>90.8</b>
GraphCore	ICLR23	95.7	-	85.7	-	-	95.9	-	86.0	-	-
FastRecon	ICCV23	97.2	-	79.3	83.5	-	97.2	-	79.3	83.5	-
MultiADS (ours)		97.5	94.1	84.3	84.8	87.2	97.7	<b>93.1</b>	83.3	87.6	88.1
MultiADS-F (ours)		<b>97.8</b>	<b>94.4</b>	86.2	<b>88.5</b>	<b>88.8</b>	<b>98</b>	92.8	85	85.2	89.1

Table 21. Few-shot anomaly detection and segmentation on the MVTec-AD Dataset. April-GAN baseline and our model are trained on the VisA dataset. (- denotes the results for this metric are not reported in the original paper; **bold** represents the best performer)

Settings		k=1					k=2				
MVTec-AD		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	89.9	64.3	62.8	75.3	68.3	92.0	70.1	67.4	75.7	71.6
PatchCore	CVPR23	95.4	80.5	79.9	81.7	82.8	96.1	82.6	81.6	82.5	84.8
WinCLIP	CVPR23	<b>96.4</b>	85.1	83.8	83.1	85.1	<b>96.8</b>	86.2	84.6	83.0	85.8
April-GAN	CVPR23	96.0	90.0	91.2	86.9	93.3	96.2	90.1	92.2	87.7	94.2
PromptAD	CVPR24	96.7	-	86.9	-	-	97.1	-	88.3	-	-
AnomalyGPT	AAAI24	96.2	-	87.4	-	-	96.4	-	88.6	-	-
MultiADS (ours)		93.2	<b>90.6</b>	<b>93</b>	<b>94</b>	<b>96.4</b>	93.2	<b>90.8</b>	<b>93.5</b>	<b>94.5</b>	<b>96.6</b>

Settings		k=4					k=8				
MVTec-AD		Pixel-Level		Image-Level			Pixel-Level		Image-Level		
Method	Venue	AUROC	AUPRO	AUROC	F1-max	AP	AUROC	AUPRO	AUROC	F1-max	AP
PaDiM	ICPR21	93.2	72.6	72.8	78.0	75.6	-	-	-	-	-
PatchCore	CVPR23	96.8	84.9	85.3	84.3	87.5	-	-	-	-	-
WinCLIP	CVPR23	97.2	87.6	87.3	84.2	88.8	-	-	-	-	-
April-GAN	CVPR23	95.9	<b>91.8</b>	92.8	92.8	96.3	<b>96.1</b>	<b>92.2</b>	93.3	93.1	96.5
PromptAD	CVPR24	<b>97.4</b>	-	89.1	-	-	-	-	-	-	-
AnomalyGPT	AAAI24	96.7	-	90.6	-	-	-	-	-	-	-
MultiADS (ours)		93.3	90.9	<b>96.6</b>	<b>95.4</b>	<b>98.1</b>	93.4	91.2	<b>97.2</b>	<b>96</b>	<b>98.5</b>

Table 22. Results for MultiADS for each product of the VisA dataset on few-shot anomaly detection and segmentation tasks. Our model is trained on the MVTec-AD dataset.

Settings	k=1							k=2						
VisA	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Candle	98.7	39.7	25.2	97	91.2	88.1	90.8	98.7	39.3	24.7	97.1	92	88.8	91
Capsules	98.1	47.1	39.9	90.7	95.4	92.1	97.6	98.3	48.8	44.2	92.9	96.5	92.5	98.1
Cashew	94.6	49.3	41.8	96.3	91	89.7	95.5	94.3	49.5	41.4	96.5	95	92.2	97.6
Chewinggum	99.7	72.4	76.1	95.1	98.4	97	99.4	99.6	71.1	73.6	94.7	98.4	96.4	99.3
Fryum	95	35.4	29.8	93	96.6	92.9	98.3	95.1	36.7	30.7	93.3	97.3	95.9	98.9
Macaroni1	99.5	33.6	26.2	95.6	90.8	84	92.9	99.5	30.1	22.8	96.1	90.6	83.7	92.3
Macaroni2	98.7	26.8	14.1	90.4	85.8	80.2	89.2	98.8	23.8	12.5	89.6	83	75.6	85.6
Pcb1	96.6	36.1	29.9	93.2	94.9	90.6	94.1	97	42.5	36.2	93.5	93.5	88.6	92.3
Pcb2	95.4	27.4	19.1	84.7	77.4	72.7	78.5	95.6	35.9	24.9	86.3	87.5	82.7	87.4
Pcb3	93.8	42.9	32.4	86.5	86.4	81.3	87.4	94.1	50.1	39.8	87.3	90.9	84	91.2
Pcb4	96.6	38.3	34	91.9	96.4	93.8	94.5	96.7	39.6	34.3	92.1	96.1	93.7	93.3
Pipe_fryum	98.1	50.1	40.8	97.8	98.9	97.5	99.3	98.1	51.1	41	97.9	99	99.5	99.3
Average	97.1	41.6	34.1	92.7	91.9	88.3	93.1	97.2	43.2	35.5	93.1	93.3	89.5	93.9

Table 23. Results for MultiADS for each product of the MPDD dataset on few-shot anomaly detection and segmentation tasks. Our model is trained on the MVTec-AD dataset.

Settings	k=1							k=2						
MPDD	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Bracket_black	97.2	18.7	11.8	89.5	74.6	81.6	80.8	98.3	35	25.3	94.3	82.4	82.1	88.9
Bracket_brown	96.2	17.6	8.7	91.1	53.3	79.7	71.4	96.2	19.9	11.1	90.1	65.8	81	78.1
Bracket_white	99.7	24.5	15.2	96.7	81.1	78.3	82.5	99.6	23.7	14.1	96.2	84.1	81.1	85
Connector	96.4	33.9	32.4	87.8	91.4	82.8	89.3	96.2	35.1	34.3	87.7	93.8	85.7	91
Metal_plate	96.3	73.1	74.8	89.8	92	90.1	97.2	96.8	75	77.8	90.7	95.7	93.7	98.5
Tubes	98.8	68.7	70.4	95.5	97.6	95.5	99.1	98.8	69.2	71.2	95.7	97.9	96.3	99.2
Average	97.4	39.4	35.6	91.7	81.7	84.6	86.7	97.7	43	39	92.4	86.6	86.6	90.1

Table 24. Results for MultiADS for each product of the MVTec-AD dataset on few-shot anomaly detection and segmentation tasks. Our model is trained on the VisA dataset.

Settings	k=1							k=2						
MVTec-AD	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Bottle	93.3	63.2	66.9	89.3	97.2	96.7	99.2	93.4	63.6	67.3	89.3	96.9	96.7	99.1
Cable	84.8	37.3	34.1	81	82.7	80.8	90.3	83.8	39.8	35.1	80.6	84.6	82.2	91
Capsule	95.3	36.6	31.1	93.6	73.6	93.4	91.6	95.4	36.7	30.6	94	72.9	93	91.4
Carpet	99.1	73.1	78	97.3	99.7	98.3	99.9	99.1	72.9	77.6	97.6	99.8	98.9	99.9
Grid	98.3	45.3	40.7	94.5	95.8	96.5	98.1	98.6	45.6	42.6	95.1	97.7	97.4	98.9
Hazelnut	98	61	63.9	96	99.8	99.3	99.9	98.2	63.1	66.4	96.2	98.9	97.9	99.3
Leather	99.6	59.3	60.8	99.2	98.9	99.5	99.6	99.6	59.1	61	99.2	100	100	100
Metal_nut	83.8	40.9	43.6	85.5	97.1	96.8	99.3	83.8	41.5	45	85.8	99.7	98.4	99.9
Pill	88.8	40.4	38.6	96.3	96.4	96.9	99.2	88.6	40.3	38.2	96.3	95.5	97.2	99
Screw	98	34.7	28.6	93.3	78.8	87.5	91.2	98	35.5	31.1	93.3	76.9	86.5	91.3
Tile	95.2	69.6	64	91.7	98	96.4	99.2	95.2	69.6	64.1	91.4	98.4	97	99.3
Toothbrush	98.1	59.2	56	95.6	99.7	98.4	99.9	98	58.7	56.4	95.5	99.7	98.4	99.9
Transistor	71.4	25	22.9	59.1	82.8	75.4	80.1	72.4	27.1	24.5	59.8	85	78.6	81.2
Wood	96.4	67.9	68.8	95.7	99.1	97.4	99.7	96.5	68.1	69.3	95.8	99.3	97.5	99.8
Zipper	97.2	63.8	63.1	91.2	95.9	96.3	98.8	97.3	64.8	64	91.4	97.4	97.1	99.3
Average	93.2	51.8	50.7	90.6	93	94	96.4	93.2	52.4	51.5	90.8	93.5	94.5	96.6

Table 25. Results for MultiADS-F for each product of the VisA dataset on few-shot anomaly detection and segmentation tasks. Our model is trained on the MVTec-AD dataset.

Settings	k=1							k=2						
VisA	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Candle	98.7	40.4	27.1	97.1	90.4	84.4	91	98.7	40	26.7	97	90.6	85.7	91.1
Capsules	97.6	47.2	40.6	88.1	93.1	91.1	96.6	97.7	48.2	42.3	89.6	93.8	89.7	96.8
Cashew	94.1	39.4	32.1	96.6	91.7	89.2	95.7	93.9	39.9	31.6	96.6	94.3	91.3	97.3
Chewinggum	99.6	77.6	82.2	93.1	98.9	97.4	99.5	99.6	77.4	81.9	93.1	98.3	97.4	99.3
Fryum	94.3	33.3	27	92	93.8	93.3	97.4	94.4	34.1	27.5	92.3	94.7	93.8	98
Macaroni1	99.5	35.7	26	96.2	89.1	82.4	91.7	99.5	35	24.5	96.4	90.3	82.4	92.5
Macaroni2	98.8	26.8	14.3	89.8	84.3	77.9	88.7	98.8	25.5	13.7	89.3	82.8	77.2	86.3
Pcb1	95.2	23.2	17.3	92	95.8	89.3	96.2	95.7	25	19.1	92.3	94.9	87.1	95.4
Pcb2	94.4	31	21.6	82.3	83.7	78.8	85.7	94.5	35	24.4	83.3	87.9	80.4	90.2
Pcb3	93.5	39.9	29.9	83.6	86.1	80.4	88	93.7	46.1	35.5	84	89.6	83	90.5
Pcb4	96.5	39.7	35.1	91.6	97.5	94.1	96.7	96.5	40.5	35.4	91.6	97.4	94.2	96.5
Pipe_fryum	97.4	43.4	34.3	97.7	99.1	99	99.4	97.4	43	33.9	97.6	99	99.5	99.3
Average	96.6	39.8	32.3	91.7	92	88.1	93.9	96.7	40.8	33	91.9	92.8	88.5	94.4

Table 26. Results for MultiADS-F for each product of the MPDD dataset on few-shot anomaly detection and segmentation tasks. Our model is trained on the MVTec-AD dataset.

Settings	k=1							k=2						
MPDD	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Bracket_black	97.6	25	18.2	91.8	73.1	77.1	82.8	98.1	32.1	23.7	94.1	78.6	81.1	86.2
Bracket_brown	95.9	18.5	9.8	88.9	54.6	79.7	74.4	95.9	21.1	13.4	87.9	65.4	81	80.6
Bracket_white	99.6	22.2	14.1	95.8	74.6	78.9	69.8	99.6	22.4	12.8	95.4	75.4	81.1	70.4
Connector	96.3	30.8	27.3	87.3	84.8	70.6	79.8	96	31.8	28.6	86.9	89	82.8	86.7
Metal_plate	97.6	80.4	78.3	93.2	98.4	97.3	99.4	98.1	82.5	81.4	94.2	98.9	97.3	99.6
Tubes	99	65.6	68.9	96	95.4	91.5	98.1	99	66.2	69.5	96.2	95.3	91.4	98
Average	97.7	40.4	36.1	92.2	80.1	82.5	84	97.8	42.7	38.2	92.4	83.8	85.8	86.9

Table 27. Results for MultiADS and the most recent baseline approach, AdaCLIP, for each product of the Real-IAD dataset on few-shot (k=4) anomaly detection and segmentation tasks. Both models are trained on the MVTec-AD dataset.

Baseline	MultiADS						AdaCLIP							
Real-IAD	Pixel-Level				Image-Level			Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP
Audiojack	98.4	54.6	49.9	89.3	75.8	72.8	77.8	97.21	42.47	37.46	-	66.2	53.68	57.39
Bottle Cap	99	41.5	34.9	92	81	71.5	81.3	98.4	34.8	30.06	-	86.84	76.87	80.65
Button Battery	97.5	47.7	46.7	89.3	72.9	75.4	82	96.69	45.7	45.98	-	69.47	74.45	78.94
End Cap	96	30.6	21.7	86.8	77.3	76.8	84.4	90.59	17.74	7.89	-	60.45	74.85	67.59
Eraser	99.8	62.2	63.8	98.6	92.2	86.2	92.5	99.09	59.5	59.52	-	71.49	60.43	67.37
Fire hood	99.5	57.2	58.6	97.8	94.1	81.5	87.5	99.36	51.82	54	-	87.76	72.36	73.05
Mint	97.2	44	36.5	76	67.9	74.7	79.1	94.16	41.09	34.41	-	64.47	74.69	75.19
Mounts	99.8	60.7	58.6	99.3	91.3	87	78.6	99.68	58.08	58.96	-	85.31	75.75	77.96
Pcb	97.5	43.1	37.5	89.2	81.7	79.6	89.5	96.13	29.74	24.58	-	77.41	78.7	85.46
Phone Battery	99.4	61.8	61.2	95.3	90.5	85.6	92.7	97.51	58.98	57.42	-	61.29	63.37	65.15
Plastic Nut	98.8	37	37.1	93.5	85.9	60.1	65.7	97.1	37.57	38.56	-	81.14	53.85	58.51
Plastic Plug	99.1	47.8	40.4	96.3	79.5	70.2	80.7	95.23	46.29	39.14	-	73.36	64.37	70.65
Porcelain Doll	99.8	45.8	45.4	99	95.2	86.2	92.7	91.65	42.4	34.37	-	63.37	52.36	50.13
Regulator	96.6	38.7	29.7	78.4	78.1	51.1	55.4	88.1	3.34	1.91	-	42.27	21.92	11.48
Rolled Strip Base	99.7	68.2	63.4	99	99	97.5	99.5	98.83	48.42	44.04	-	65.33	80.32	80.01
Sim Card Set	99.8	68.7	72.6	98.4	97.3	94	97.8	99.72	66.37	71.28	-	83.06	79.91	86.61
Switch	92.8	24.5	19.2	86.3	80.3	81.6	89	83.55	21.81	15.82	-	82.29	82.49	89.5
Tape	99.8	58.8	57.5	99.4	98.4	92.8	97.9	98.6	48.59	46.93	-	96.95	89.64	95.18
Terminalblock	99	65.2	60.7	96.7	92.8	89.9	95.9	98.53	52.16	50.18	-	61.13	71.85	68.61
Toothbrush	98	47.1	40.4	93.7	87.3	84.3	92.8	98.48	45.37	43.02	-	61.84	78.65	69.81
Toy	84.2	26	17.8	75.8	80.3	83.3	89.9	80.32	19.47	12.37	-	47.04	80.13	68.09
Toy Brick	98.9	56.5	56.9	91.2	85.9	75.6	85.2	97.73	32.03	25.41	-	54.69	59.04	43.9
Transistor	94.7	37	27.2	80.2	79.4	80.3	88.6	86.28	21.05	12.47	-	59.39	77.97	72.56
U Block	99.2	53.8	50.2	95.8	87.7	77.3	83.3	95.71	32.23	22.41	-	78.29	69.38	75.75
Usb	99.1	47.5	41.4	96.7	83.1	73.9	82.6	96.67	49.59	45.06	-	54.48	39.1	39.55
Usb Adaptor	98.8	37.8	28.4	92.5	86.9	77.5	84.3	97.63	42.81	33.58	-	80.96	74.29	80.75
Vcpill	98.3	67	65.4	88.5	84.3	74.8	82	95.45	43.35	40.93	-	52.28	51.11	43.74
Wooden Beads	98.4	47.6	44.2	89.6	79.5	75.4	86.2	95.39	19.8	13.34	-	69.82	72.57	77.64
Woodstick	99.1	63.7	66.7	96.7	92	72.7	78.9	99.57	58.02	59.74	-	78.77	54	51.17
Zipper	98	40.7	36.9	96.1	97.9	96.6	98.8	98.51	44.78	41.15	-	88.31	86.38	94.81
Average	97.9	49.4	45.7	91.9	85.8	79.5	85.8	95.39	40.51	36.73	-	70.18	68.15	68.57

Table 28. Results for MultiADS and the most competitive baseline approach, April-GAN, for each product of the MAD dataset on few-shot (k=4) anomaly detection and segmentation tasks. Both models are trained on the MVTec-AD dataset.

Baseline	MultiADS						April-GAN								
MAD	Pixel-Level				Image-Level				Pixel-Level				Image-Level		
Product	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	AUROC	F1-max	AP	AUPRO	AUROC	F1-max	AP	
Bear	91.8	16.9	11.9	82.9	71.9	93.7	94.6	91.2	13.1	8.5	79.8	64.1	93.5	92.5	
Bird	91.5	9.3	4.9	76.6	64.8	94.4	92.6	90.8	7.9	4.6	74.4	66.3	94.4	93.8	
Cat	94.4	8.7	4.9	86.4	57	94.5	92.3	94.1	9.2	5.6	84.5	58.4	94.5	92.6	
Elephant	72.5	6.7	3.8	67.4	72.9	93.9	95.8	71.5	6.7	3.7	65.7	64.6	93.9	94	
Gorilla	93.3	11.8	5.9	82.2	52.1	96.2	92.7	92.3	10.1	5.7	77.3	55.4	96.2	93.9	
Mallard	86.9	14.4	6.7	67.2	62	95.6	95	86.3	15.4	8	64.6	55.7	95.6	93.8	
Obesobeso	95.1	20.7	13.2	89.5	58.7	94.5	90.8	94.2	17.2	11.6	86.5	64.2	94.1	93.7	
Owl	92.8	15.9	9.6	81.4	72.6	93.2	94.2	92.4	12.5	7.5	79.7	67	93	93.4	
Parrot	85.7	9.2	5.1	66	66.5	92	91.7	85.2	7.2	4.4	68.5	59	91.8	89.8	
Phoenix	85.7	4.4	2	73.9	52.6	94.4	90.3	85.4	4.8	2.3	73.2	53.8	94.4	90.6	
Pig	95.5	13.9	10.2	86.5	61	94	93.2	95.3	14	9.5	85	62.9	94	93.9	
Puppy	88.2	12.8	7.7	75.2	68.7	92.9	94.1	87.5	9.8	6.9	72.6	63.4	92.9	92.6	
Sabertooth	91.7	6.4	4.7	77.6	63.8	93.2	92.9	91	5.9	4.2	74.9	60.6	93.1	91.9	
Scorpion	90.7	8.7	6.2	82.7	62.1	92.9	91.8	91	8.8	6.8	81.7	65.2	92.9	93.3	
Sheep	94.2	12.5	9	85.4	63.5	93.3	93.1	94.2	12.1	8.8	84.6	60.5	93.3	92.7	
Swan	91	10.6	4.3	77.4	51	93.3	89.1	90.7	8.5	3.9	76.4	57.3	93.3	90.4	
Turtle	91.5	12.6	7.7	77	59.6	95.2	93.7	90.9	15.4	9.4	74.2	62.6	95.2	95	
Unicorn	87.6	5.1	4.1	74.3	54.6	95.7	94	87.3	5.3	4	71.3	60	95.7	95	
Whale	89.5	13.3	7.4	82	58.1	94.4	92.8	89.3	16.1	9.2	80.7	67.5	94.7	94.7	
Zalika	86.6	6.6	4.9	68.9	68	93.5	93.8	86	6	4.6	65.9	65.8	93.1	93.5	
Average	89.8	11	6.7	78	62.1	94	92.9	89.3	10.3	6.5	76.1	61.7	94	93.1	

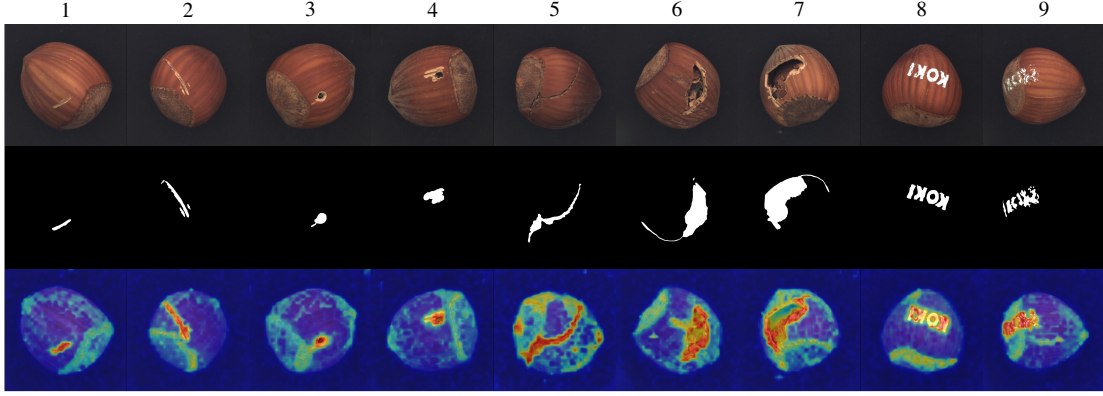


Figure 1. This visualization showcases the **hazelnut** product from the MVTec AD dataset (trained on the VisA dataset). The first row displays the input images, the second row presents the ground truth masks of anomalies, and the third row shows the predicted anomaly maps generated by the model. The model is trained on the VisA dataset and evaluated on the MVTec AD dataset using a few-shot setting with  $k = 4$ . As shown in the figure, our approach effectively distinguishes defect types such as **scratches** (Columns 1, 2) and **holes** (Columns 3, 4). However, for large **cracks** (Columns 6, 7), the method tends to focus on the edges while marking the interior as normal. This behavior is likely due to the patch-level features being more localized and lacking global context.

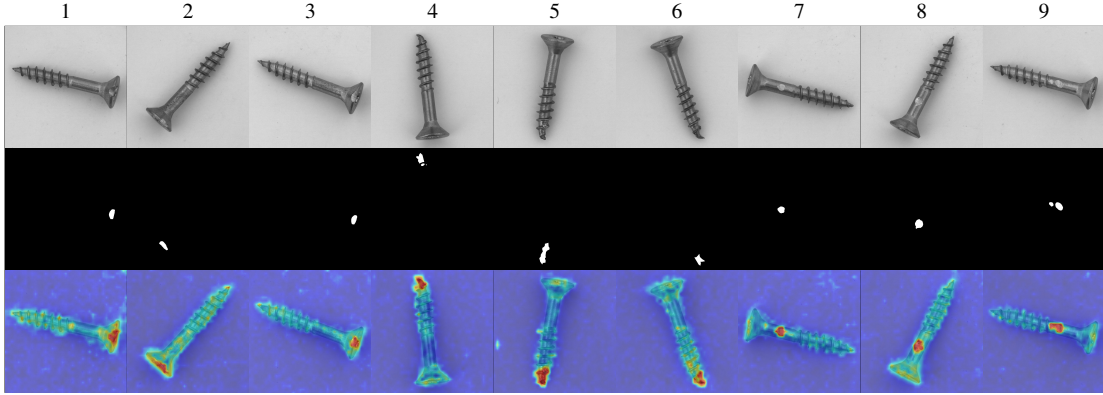


Figure 2. This visualization showcases the **screw** product from the MVTec AD dataset (trained on the VisA dataset). Our model successfully detects defects such as **scratches** (Columns 1-3, 7-9) and **bends** (Columns 4-6) in the front part. Our model also allocates some attention to the screw body.

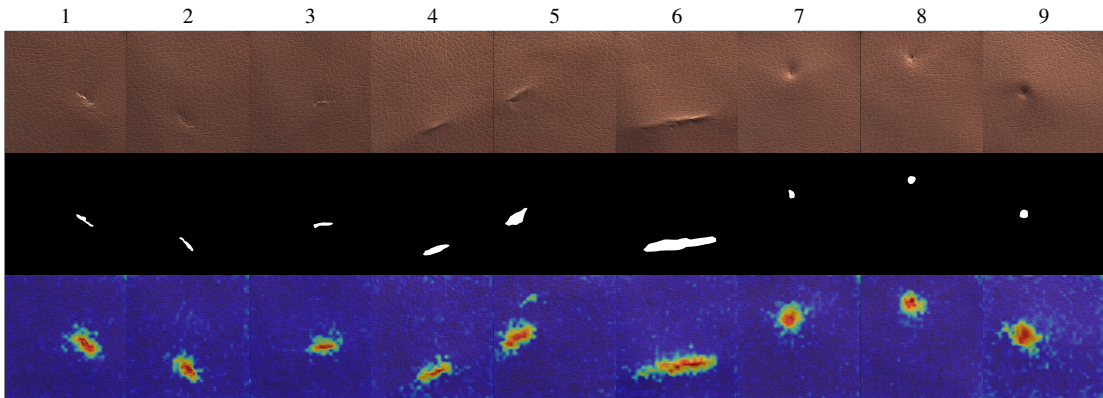


Figure 3. This visualization showcases the **leather** product from the MVTec AD dataset. Our approach can easily identify the defect of **cut** (Columns 1-3), **fold** (Columns 4-6), and **poke** (Columns 7-9).



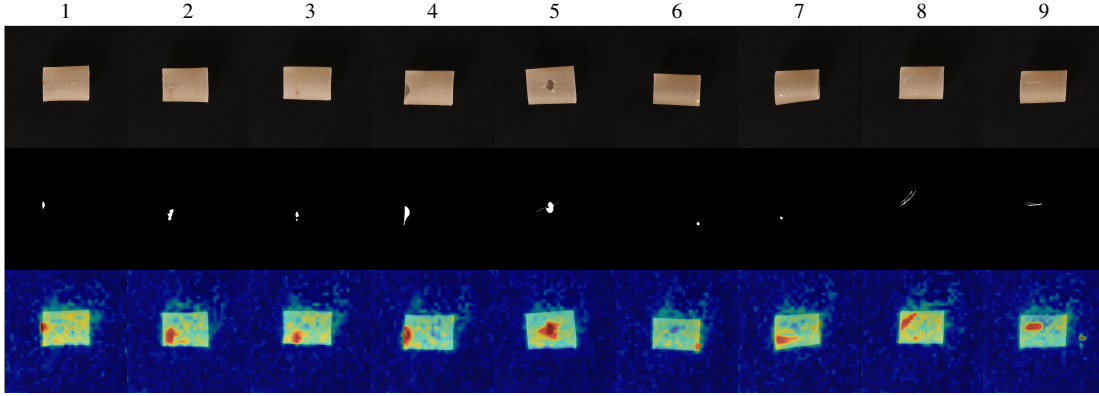


Figure 4. This visualization showcases the **pipe\_fryum** product from the VisA dataset (trained on the MVTec-AD dataset). Our model can identify the defects like **color spots** (Columns 1-3), **broken** (Columns 4-5), and **scratches** (Columns 6-9).

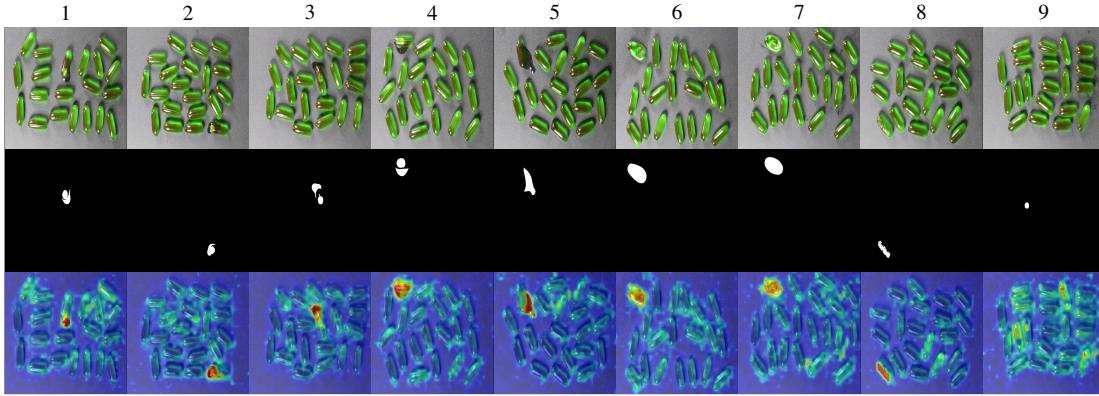


Figure 5. This visualization showcases the **capsule** product from the VisA dataset (trained on the MVTec-AD dataset). Our model effectively identifies defects such as **leakage** (Columns 1–5), **misshapes** (Columns 6–7), and **scratches** (Column 8) with clear accuracy. However, it tends to overlook **bubble** defect (Columns 1 and 9), and product highlights are occasionally misclassified as defects (Column 9).

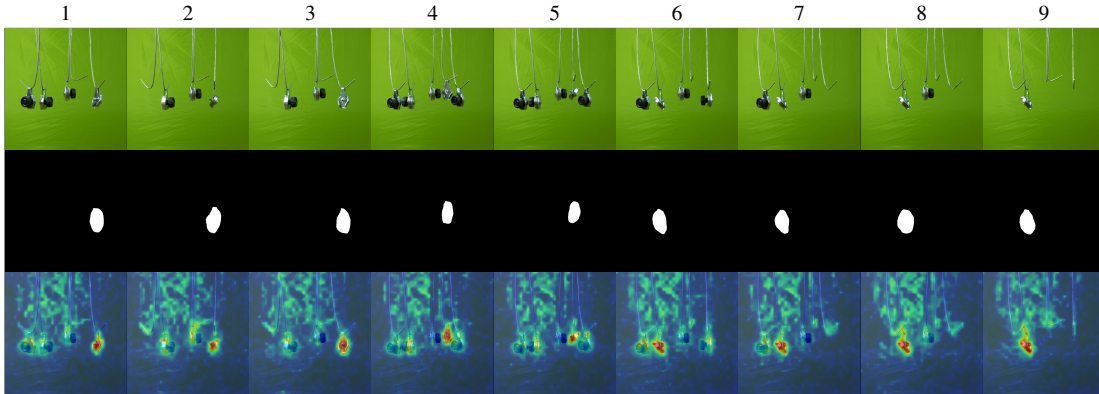


Figure 6. This visualization showcases the **connector** product from the MPDD dataset (trained on the MVTec-AD dataset). Our model effectively identifies **part-missing** defects. However, wrinkles in the green background can sometimes mislead the model, causing them to be misclassified as anomalies.

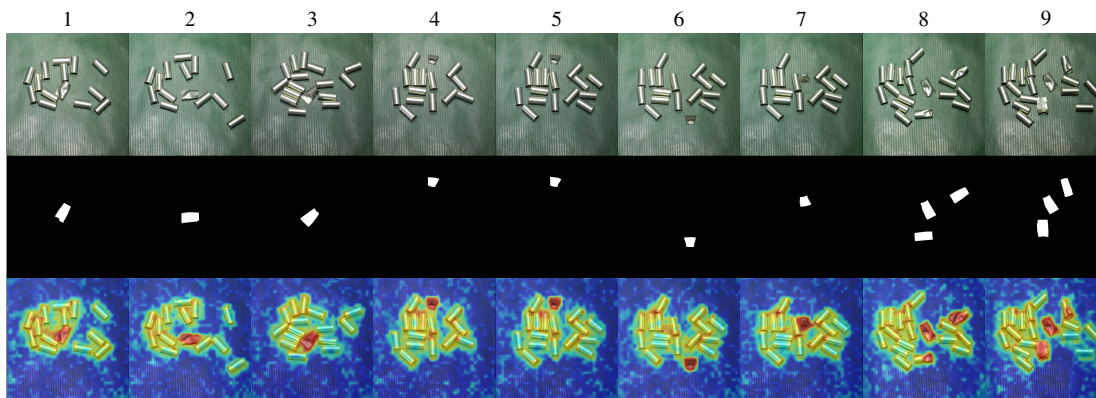


Figure 7. This visualization showcases the **tube** product from the MPDD dataset (trained on the MVTec-AD dataset). Our model successfully identifies **flattened** tubes but also introduces some noise, such as misclassifying the edges of the tubes as anomalies.

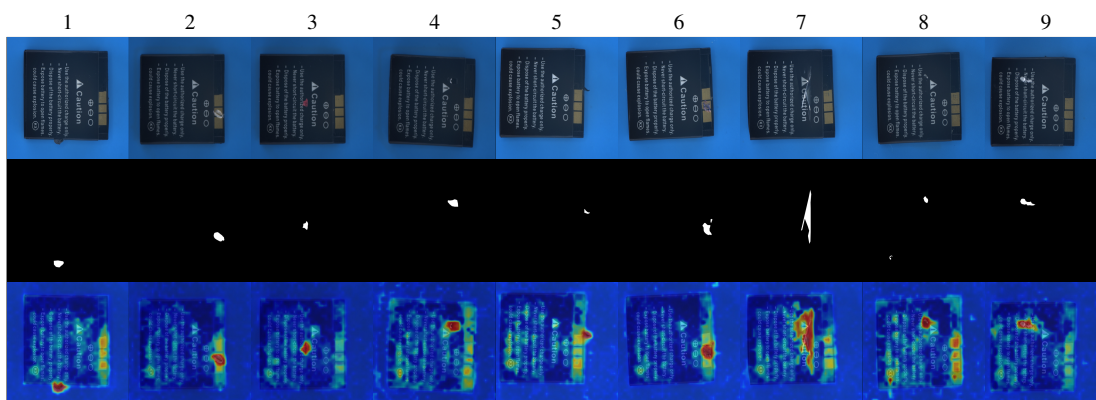


Figure 8. This visualization showcases the **phone battery** product from the Real-IAD dataset (trained on the MVTec-AD dataset). Our model successfully identifies defects like **contamination**, **scratch**, and **damage**.

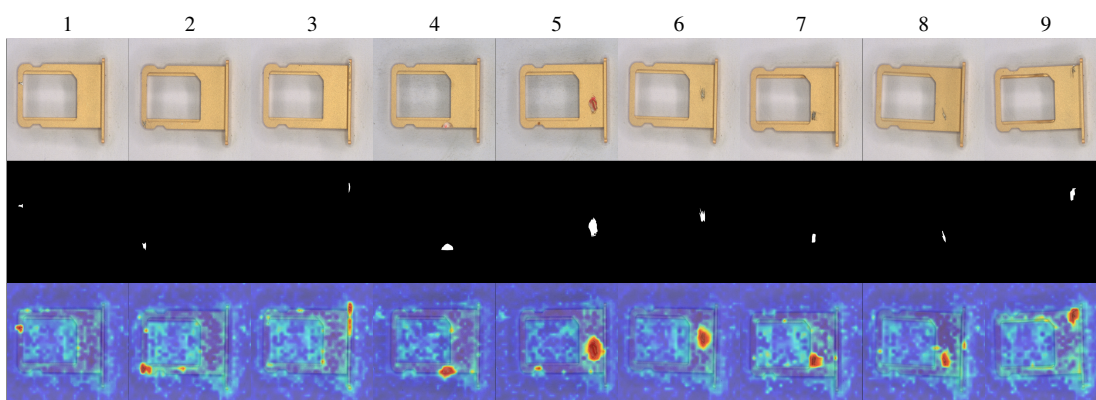


Figure 9. This visualization showcases the **sim card set** product from the Real-IAD dataset (trained on the MVTec-AD dataset). Our model successfully identifies defects like **scratch** and **damage**.

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